















ESD

TVS

MOS

LDO

Diode

Sensor

DC-DC

Product Specification

Domestic Part Number	IRFZ46N
Overseas Part Number	IRFZ46N
▶ Equivalent Part Number	IRFZ46N





- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

Product Summary

BVDSS	RDSON	ID
60V	12mΩ	60A

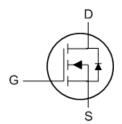
Description

The IRFZ46N is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The IRFZ46N meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

TO220 Pin Configuration





Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	60	А
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	38	А
ID@T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	9.2	А
ID@TA=70°C	Continuous Drain Current, V _{GS} @ 10V ¹	7.5	А
I _{DM}	Pulsed Drain Current ²	165	А
EAS	Single Pulse Avalanche Energy ³	73	mJ
I _{AS}	Avalanche Current	38	Α
P _D @T _C =25°C	Total Power Dissipation ⁴	86.8	W
P _D @T _A =25°C	Total Power Dissipation ⁴	2	W
T _{STG}	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
R _θ JA	Thermal Resistance Junction-Ambient ¹		62	°C/W
Rejc	Thermal Resistance Junction-Case ¹		1.44	°C/W



Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60			V
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA		0.052		V/°C
D	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =30A			12	
R _{DS(ON)}		V _{GS} =4.5V , I _D =15A			15	mΩ
V _{GS(th)}	Gate Threshold Voltage	V V I 250A	1.2		2.5	V
△VGS(th)	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250uA$		-5.76		mV/°C
	Dunin Course Looke as Course	V _{DS} =48V , V _{GS} =0V , T _J =25°C			1	
I _{DSS}	Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , T _J =55°C			5	- uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =30A		42		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.5		Ω
Qg	Total Gate Charge (4.5V)	V _{DS} =48V , V _{GS} =4.5V , I _D =15A		28.7		
Q _{gs}	Gate-Source Charge			10.5		nC
Q _{gd}	Gate-Drain Charge			9.9		1
T _{d(on)}	Turn-On Delay Time			10.4		
Tr	Rise Time	V _{DD} =30V , V _{GS} =10V , R _G =3.3Ω, I _D =15A		9.2		
T _{d(off)}	Turn-Off Delay Time			63		ns
Tf	Fall Time			4.8		1
Ciss	Input Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		3240		
Coss	Output Capacitance			210		pF
Crss	Reverse Transfer Capacitance			146		

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,5}	V V OV Force Current			60	Α
I _{SM}	Pulsed Source Current ^{2,5}	$V_G=V_D=0V$, Force Current			165	Α
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25°C			1.2	V
t _{rr}	Reverse Recovery Time			18		nS
Q _{rr}	Reverse Recovery Charge	IF=15A , dl/dt=100A/μs , T _J =25°C		14		nC

Note

- 1. The data tested by surface mounted on a 1 inch $^2\,\text{FR-4}$ board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\,\leq\,300\text{us}$, duty cycle $\,\leq\,2\%$
- 3. The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V, L=0.1mH, I_{AS} =38A
- 4.The power dissipation is limited by 150 $^{\circ}\text{C}\;$ junction temperature
- 5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics

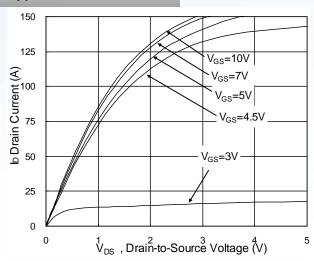


Fig.1 Typical Output Characteristics

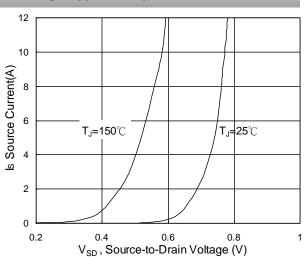


Fig.3 Forward Characteristics of Reverse

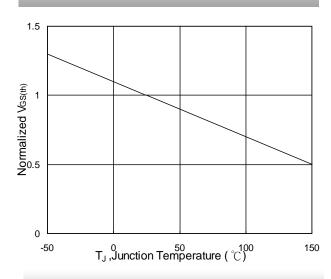


Fig.5 Normalized V_{GS(th)} v.s T_J

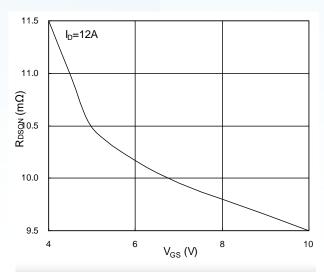


Fig.2 On-Resistance v.s Gate-Source

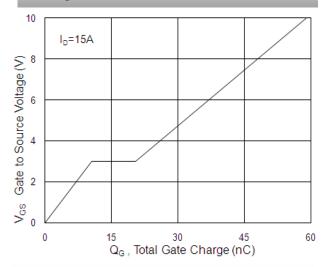


Fig.4 Gate-Charge Characteristics

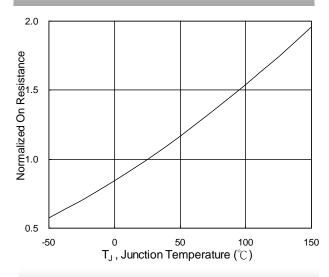
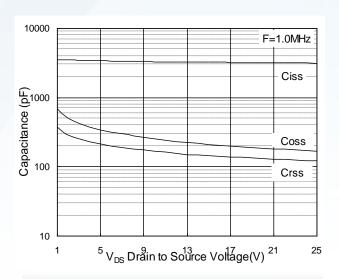


Fig.6 Normalized R_{DSON} v.s T_J





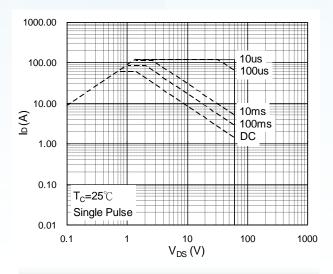


Fig.7 Capacitance

Fig.8 Safe Operating Area

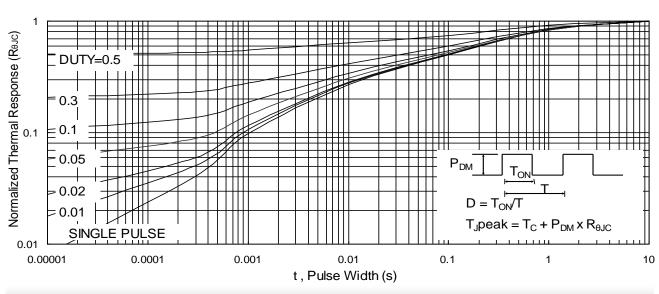


Fig.9 Normalized Maximum Transient Thermal Impedance

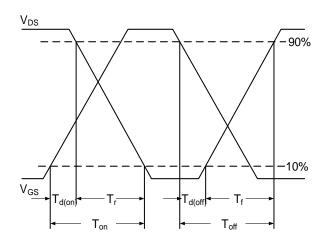


Fig.10 Switching Time Waveform

Fig.11 Unclamped Inductive Switching Waveform



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